Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,986	JUNG, YUN-HO	
Examiner	Art Unit	
Stephen W. Smoot	2813	

SEARCHED				
Class	Subclass	Date	Examiner	
219	121.6	2/18/2005	· sws	
250	492.22	2/18/2005	SWS.	
257	75	2/18/2005	sws	
257	E21.134	2/18/2005	sws	
430	5	2/18/2005	sws	
438	487	2/18/2005	sws	
438	943	2/18/2005	sws	
438	946	2/18/2005	sws	

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
	-				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Key Words: Sequential Lateral Solidification - SLS, Crystallization, Grain Growth;	2/18/2005	LW.S. sws		
Amorphous Silicon; Polysilicon; Mask; Laser.	2/18/2005	8,W,8, sws		
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	2/18/2005	LW.S sws		